

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/076,215	<b>Applicant(s)/Patent under Reexamination</b>  GOERTZEN, KENBE D.
<b>Examiner</b>  Y. Lee	<b>Art Unit</b>  2621	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner